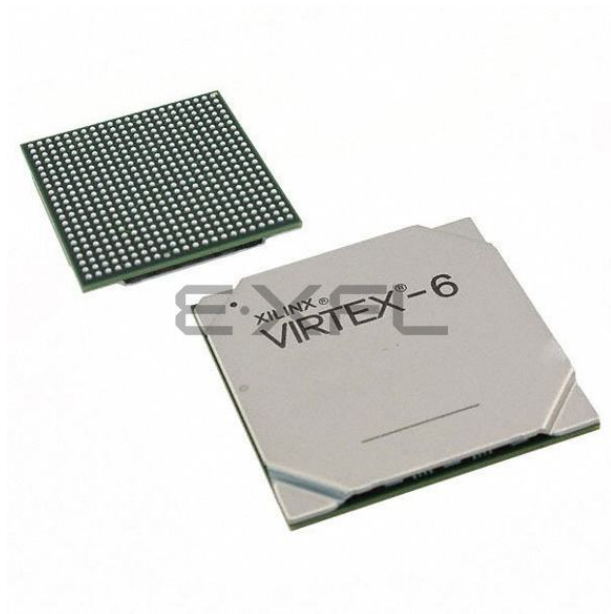




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Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Product Status	Active
Number of LABs/CLBs	37200
Number of Logic Elements/Cells	476160
Total RAM Bits	39223296
Number of I/O	840
Number of Gates	-
Voltage - Supply	0.95V ~ 1.05V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	1759-BBGA, FCBGA
Supplier Device Package	1759-FCBGA (42.5x42.5)
Purchase URL	https://www.e-xfl.com/product-detail/xilinx/xc6vsx475t-2ff1759c

Table 4: Typical Quiescent Supply Current (Cont'd)

Symbol	Description	Device	Speed and Temperature Grade						Units
			-3 (C)	-2 (C, E, & I)	-1 (C & I)	-1 (I & M) ⁽²⁾	-1L (C)	-1L (I) ⁽¹⁾	
I _{CCOQ}	Quiescent V _{CCO} supply current	XC6VLX75T	1	1	1	N/A	1	1	mA
		XC6VLX130T	1	1	1	N/A	1	1	mA
		XC6VLX195T	1	1	1	N/A	1	1	mA
		XC6VLX240T	2	2	2	N/A	2	2	mA
		XC6VLX365T	2	2	2	N/A	2	2	mA
		XC6VLX550T ⁽³⁾	N/A	3	3	N/A	3	3	mA
		XC6VLX760 ⁽³⁾	N/A	3	3	N/A	3	3	mA
		XC6VSX315T	2	2	2	N/A	2	2	mA
		XC6VSX475T ⁽³⁾	N/A	2	2	N/A	2	2	mA
		XC6VHX250T	1	1	1	N/A	N/A	N/A	mA
		XC6VHX255T	1	1	1	N/A	N/A	N/A	mA
		XC6VHX380T ⁽⁴⁾	2	2	2	N/A	N/A	N/A	mA
		XC6VHX565T ⁽⁵⁾	N/A	2	2	N/A	N/A	N/A	mA
		XQ6VLX130T	N/A	1	N/A	1	N/A	1	mA
		XQ6VLX240T	N/A	2	N/A	2	N/A	2	mA
		XQ6VLX550T ⁽⁷⁾	N/A	N/A	N/A	3	N/A	3	mA
		XQ6VSX315T	N/A	2	N/A	2	N/A	2	mA
		XQ6VSX475T ⁽⁷⁾	N/A	N/A	N/A	2	N/A	2	mA

Table 4: Typical Quiescent Supply Current (Cont'd)

Symbol	Description	Device	Speed and Temperature Grade						Units
			-3 (C)	-2 (C, E, & I)	-1 (C & I)	-1 (I & M) ⁽²⁾	-1L (C)	-1L (I) ⁽¹⁾	
I _{CCAUXQ}	Quiescent V _{CCAUX} supply current	XC6VLX75T	45	45	45	N/A	45	45	mA
		XC6VLX130T	75	75	75	N/A	75	75	mA
		XC6VLX195T	113	113	113	N/A	113	113	mA
		XC6VLX240T	135	135	135	N/A	135	135	mA
		XC6VLX365T	191	191	191	N/A	191	191	mA
		XC6VLX550T ⁽³⁾	N/A	286	286	N/A	286	286	mA
		XC6VLX760 ⁽³⁾	N/A	387	387	N/A	387	387	mA
		XC6VSX315T	186	186	186	N/A	186	186	mA
		XC6VSX475T ⁽³⁾	N/A	279	279	N/A	279	279	mA
		XC6VHX250T	152	152	152	N/A	N/A	N/A	mA
		XC6VHX255T	152	152	152	N/A	N/A	N/A	mA
		XC6VHX380T ⁽⁴⁾	227	227	227	N/A	N/A	N/A	mA
		XC6VHX565T ⁽⁵⁾	N/A	315	315	N/A	N/A	N/A	mA
		XQ6VLX130T ⁽⁶⁾	N/A	75	N/A	75	N/A	75	mA
		XQ6VLX240T ⁽⁶⁾	N/A	135	N/A	135	N/A	135	mA
		XQ6VLX550T ⁽⁷⁾	N/A	N/A	N/A	286	N/A	286	mA
		XQ6VSX315T ⁽⁶⁾	N/A	186	N/A	186	N/A	186	mA
		XQ6VSX475T ⁽⁷⁾	N/A	N/A	N/A	279	N/A	279	mA

Notes:

- Typical values are specified at nominal voltage, 85°C junction temperatures (T_j). -1 and -2 industrial (I) grade devices have the same typical values as commercial (C) grade devices at 85°C, but higher values at 100°C. Use the XPE tool to calculate 100°C values. -1L industrial temperature range devices have the values specified in this column.
- Use the XPE tool to calculate 125°C values for -1M temperature range devices.
- The -2E extended temperature range (T_j = 0°C to +100°C) is only available in these devices. The -2I temperature range (T_j = -40°C to +100°C) is available for all other devices except the XC6VHX565T.
- The XC6VHX380T is available with both -2E and -2I temperature ranges.
- The XC6VHX565T is only available in the following temperature ranges: -1C, -1I, -2C, and -2E.
- The XQ6VLX130T, XQ6VLX240T, and XQ6VSX315T are available in -2I, -1I, -1M, and -1LI temperature ranges.
- The XQ6VLX550T and the XQ6VSX475T are only available in -1I and -1LI temperature ranges.
- Typical values are for blank configured devices with no output current loads, no active input pull-up resistors, all I/O pins are 3-state and floating.
- If DCI or differential signaling is used, more accurate quiescent current estimates can be obtained by using the XPE or XPower Analyzer (XPA) tools.

GTH Transceiver DC Input and Output Levels

Table 30 summarizes the DC output specifications of the GTH transceivers in Virtex-6 FPGAs. Consult [UG371: Virtex-6 FPGA GTH Transceivers User Guide](#) for further details.

Table 30: GTH Transceiver DC Specifications

Symbol	DC Parameter	Conditions	Min	Typ	Max	Units
D_{VPPIN}	Differential peak-to-peak input voltage	External AC coupled	175	–	1200	mV
D_{VPPOUT}	Differential peak-to-peak output voltage ⁽¹⁾	Transmitter output swing is set to maximum setting	800	–	1200	mV
R_{IN}	Differential input resistance		80	100	120	Ω
R_{OUT}	Differential output resistance		80	100	120	Ω
T_{OSKEW}	Transmitter output pair (TXP and TXN) intra-pair skew		–	2	–	ps
C_{EXT}	Recommended external AC coupling capacitor ⁽²⁾		–	100	–	nF

Notes:

1. The output swing and preemphasis levels are programmable using the attributes discussed in [UG371: Virtex-6 FPGA GTH Transceivers User Guide](#) and can result in values lower than reported in this table.
2. Other values can be used as appropriate to conform to specific protocols and standards.

Table 31 summarizes the DC specifications of the clock input of the GTH transceiver. Consult [UG371: Virtex-6 FPGA GTH Transceivers User Guide](#) for further details.

Table 31: GTH Transceiver Clock DC Input Level Specification

Symbol	DC Parameter	Conditions	Min	Typ	Max	Units
V_{IDIFF}	Differential peak-to-peak input voltage	≤ 600 MHz	500	–	1600	mV
		> 600 MHz	600	–	1600	mV
R_{IN}	Differential input resistance		80	100	120	Ω
C_{EXT}	Required external AC coupling capacitor		–	100	–	nF

GTH Transceiver Switching Characteristics

Consult [UG371: Virtex-6 FPGA GTH Transceivers User Guide](#) for further information.

Table 32: GTH Transceiver Maximum Data Rate and PLL Frequency Range

Symbol	Description	Conditions	Speed Grade			Units
			-3	-2	-1	
F_{GTHMAX}	Maximum GTH transceiver data rate	PLL Output Divider = 1	11.182	11.182	10.32	Gb/s
		PLL Output Divider = 4	2.795	2.795	2.58	Gb/s
F_{GTHMIN}	Minimum GTH transceiver data rate ⁽¹⁾	PLL Output Divider = 1	9.92	9.92	9.92	Gb/s
		PLL Output Divider = 4	2.48	2.48	2.48	Gb/s
$F_{GPLLMAX}$	Maximum GTH PLL frequency		5.591	5.591	5.16	GHz
$F_{GPLLMIN}$	Minimum GTH PLL frequency		4.96	4.96	4.96	GHz

Notes:

- Lower data rates can be achieved using FPGA logic based oversampling designs.

Table 33: GTH Transceiver Dynamic Reconfiguration Port (DRP) Switching Characteristics

Symbol	Description	Speed Grade			Units
		-3	-2	-1	
$F_{GTHDRPCLK}$	GTHDRPCLK maximum frequency	70	70	60	MHz

Table 34: GTH Transceiver Reference Clock Switching Characteristics

Symbol	Description	Conditions	All Speed Grades			Units
			Min	Typ	Max	
F_{GCLK}	Reference clock frequency range	-1 speed grade	150	—	645	MHz
		-2 and -3 speed grades	150	—	700	MHz
T_{RCLK}	Reference clock rise time	20% – 80%	—	200	—	ps
T_{FCLK}	Reference clock fall time	80% – 20%	—	200	—	ps
T_{DCREF}	Reference clock duty cycle	CLK	45	50	55	%
T_{LOCK}	Clock recovery frequency acquisition time	Initial PLL lock	—	—	2	ms
T_{PHASE}	Clock recovery phase acquisition time	Lock to data after PLL has locked to the reference clock	—	—	20	μs

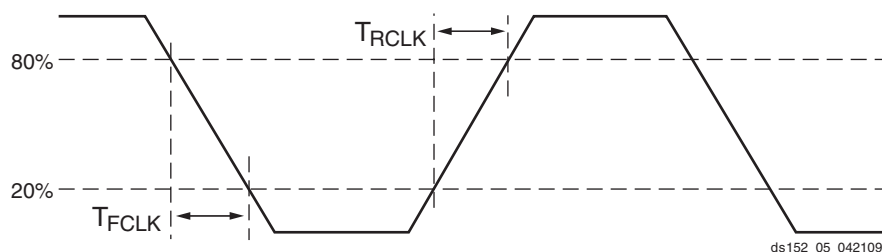


Figure 5: Reference Clock Timing Parameters

Table 35: GTH Transceiver User Clock Switching Characteristics ⁽¹⁾

Symbol	Description	Conditions	Speed Grade			Units
			-3	-2	-1	
F _{TXOUT}	TXUSERCLKOUT maximum frequency		350	350	323	MHz
F _{RXOUT}	RXUSERCLKOUT maximum frequency		350	350	323	MHz
F _{TXIN}	TXUSERCLKIN maximum frequency	16-bit data path	350	350	323	MHz
		20-bit data path	280	280	258	MHz
		32-bit data path	350	350	323	MHz
		40-bit data path	280	280	258	MHz
		64-bit data path	175	175	162	MHz
		80-bit data path	140	140	129	MHz
		64B/66B-bit data path	170	170	157	MHz
F _{RXIN}	RXUSERCLKIN maximum frequency	16-bit data path	350	350	323	MHz
		20-bit data path	280	280	258	MHz
		32-bit data path	350	350	323	MHz
		40-bit data path	280	280	258	MHz
		64-bit data path	175	175	162	MHz
		80-bit data path	140	140	129	MHz
		64B/66B-bit data path	170	170	157	MHz

Notes:

1. Clocking must be implemented as described in [UG371](#): Virtex-6 FPGA GTH Transceivers User Guide.

Table 36: GTH Transceiver Transmitter Switching Characteristics

Symbol	Description	Condition	Min	Typ	Max	Units
T _{RTX}	TX Rise time	20%–80%	–	50 ⁽³⁾	–	ps
T _{FTX}	TX Fall time	80%–20%	–	50 ⁽³⁾	–	ps
T _{LLSKEW}	TX lane-to-lane skew	within one GTH Quad	–	–	300	ps
Transmitter Output Jitter⁽¹⁾⁽²⁾						
TJ _{11.18}	Total Jitter	11.181 Gb/s	–	–	0.280	UI
DJ _{11.18}	Deterministic Jitter		–	–	0.170	UI
TJ _{10.3125}	Total Jitter	10.3125 Gb/s	–	–	0.280	UI
DJ _{10.3125}	Deterministic Jitter		–	–	0.170	UI
TJ _{9.953}	Total Jitter	9.953 Gb/s	–	–	0.280	UI
DJ _{9.953}	Deterministic Jitter		–	–	0.170	UI
TJ _{2.667}	Total Jitter	2.667 Gb/s	–	–	0.110	UI
DJ _{2.667}	Deterministic Jitter		–	–	0.060	UI
TJ _{2.488}	Total Jitter	2.488 Gb/s	–	–	0.110	UI
DJ _{2.488}	Deterministic Jitter		–	–	0.060	UI

Notes:

1. These values are NOT intended for protocol specific compliance determinations.
2. All jitter values are based on a bit-error ratio of 1e⁻¹².
3. Rise and fall times are specified at the transmitter package balls.

Integrated Interface Block for PCI Express Designs Switching Characteristics

More information and documentation on solutions for PCI Express designs can be found at:

<http://www.xilinx.com/technology/protocols/pciexpress.htm>

Table 39: Maximum Performance for PCI Express Designs

Symbol	Description	Speed Grade				Units
		-3	-2	-1	-1L	
F _{PIPECLK}	Pipe clock maximum frequency	250	250	250	250	MHz
F _{USERCLK}	User clock maximum frequency	500	500	250	250	MHz
F _{DRPCLK}	DRP clock maximum frequency	250	250	250	250	MHz

System Monitor Analog-to-Digital Converter Specification

Table 40: Analog-to-Digital Specifications

Parameter	Symbol	Comments/Conditions	Min	Typ	Max	Units
AV _{DD} = 2.5V ± 5%, V _{REFP} = 1.25V, V _{REFN} = 0V, ADCCLK = 5.2 MHz, T _j = -55°C to 125°C M-Grade, Typical values at T _j = +35°C						
DC Accuracy: All external input channels. Both unipolar and bipolar modes.						
Resolution			10	—	—	Bits
Integral Nonlinearity	INL		—	—	±1	LSBs
Differential Nonlinearity	DNL	No missing codes (T _{MIN} to T _{MAX}) Guaranteed Monotonic	—	—	±0.9	LSBs
Unipolar Offset Error ⁽¹⁾		Uncalibrated	—	±2	±30	LSBs
Bipolar Offset Error ⁽¹⁾		Uncalibrated measured in bipolar mode	—	±2	±30	LSBs
Gain Error		Uncalibrated - External Reference	—	±0.2	±2	%
		Uncalibrated - Internal Reference	—	±2	—	%
Bipolar Gain Error ⁽¹⁾		Uncalibrated - External Reference	—	±0.2	±2	%
		Uncalibrated - Internal Reference	—	±2	—	%
Total Unadjusted Error (Uncalibrated)	TUE	Deviation from ideal transfer function. External 1.25V reference	—	±10	—	LSBs
		Deviation from ideal transfer function. Internal reference	—	±20	—	LSBs
Total Unadjusted Error (Calibrated)	TUE	Deviation from ideal transfer function. External 1.25V reference	—	±1	±2	LSBs
Calibrated Gain Temperature Coefficient		Variation of FS code with temperature	—	±0.01	—	LSB/°C
DC Common-Mode Reject	CMRR _{DC}	V _N = V _{CM} = 0.5V ± 0.5V, V _P - V _N = 100mV	—	70	—	dB
Conversion Rate ⁽²⁾						
Conversion Time - Continuous	t _{CONV}	Number of CLK cycles	26	—	32	
Conversion Time - Event	t _{CONV}	Number of CLK cycles	—	—	21	
T/H Acquisition Time	t _{ACQ}	Number of CLK cycles	4	—	—	
DRP Clock Frequency	DCLK	DRP clock frequency	8	—	80	MHz
ADC Clock Frequency	ADCCLK	Derived from DCLK	1	—	5.2	MHz
CLK Duty cycle			40	—	60	%

Table 44: IOB Switching Characteristics for the Commercial (XC) Virtex-6 Devices (Cont'd)

I/O Standard	T _{IOPI}				T _{IOOP}				T _{IOTP}				Units
	Speed Grade				Speed Grade				Speed Grade				
	-3	-2	-1	-1L	-3	-2	-1	-1L	-3	-2	-1	-1L	
LVC MOS25, Fast, 24 mA	0.51	0.57	0.66	0.70	1.66	1.79	1.99	1.96	1.66	1.79	1.99	1.96	ns
LVC MOS18, Slow, 2 mA	0.55	0.61	0.71	0.73	4.21	4.47	4.87	4.30	4.21	4.47	4.87	4.30	ns
LVC MOS18, Slow, 4 mA	0.55	0.61	0.71	0.73	2.79	2.96	3.21	2.94	2.79	2.96	3.21	2.94	ns
LVC MOS18, Slow, 6 mA	0.55	0.61	0.71	0.73	2.30	2.43	2.64	2.47	2.30	2.43	2.64	2.47	ns
LVC MOS18, Slow, 8 mA	0.55	0.61	0.71	0.73	2.01	2.11	2.27	2.24	2.01	2.11	2.27	2.24	ns
LVC MOS18, Slow, 12 mA	0.55	0.61	0.71	0.73	1.88	1.99	2.15	2.10	1.88	1.99	2.15	2.10	ns
LVC MOS18, Slow, 16 mA	0.55	0.61	0.71	0.73	1.84	1.95	2.11	2.04	1.84	1.95	2.11	2.04	ns
LVC MOS18, Fast, 2 mA	0.55	0.61	0.71	0.73	4.00	4.23	4.57	4.08	4.00	4.23	4.57	4.08	ns
LVC MOS18, Fast, 4 mA	0.55	0.61	0.71	0.73	2.62	2.76	2.97	2.74	2.62	2.76	2.97	2.74	ns
LVC MOS18, Fast, 6 mA	0.55	0.61	0.71	0.73	2.15	2.28	2.46	2.32	2.15	2.28	2.46	2.32	ns
LVC MOS18, Fast, 8 mA	0.55	0.61	0.71	0.73	1.90	1.99	2.13	2.14	1.90	1.99	2.13	2.14	ns
LVC MOS18, Fast, 12 mA	0.55	0.61	0.71	0.73	1.69	1.80	1.97	1.88	1.69	1.80	1.97	1.88	ns
LVC MOS18, Fast, 16 mA	0.55	0.61	0.71	0.73	1.63	1.74	1.91	1.88	1.63	1.74	1.91	1.88	ns
LVC MOS15, Slow, 2 mA	0.64	0.73	0.85	0.85	3.43	3.77	4.29	3.91	3.43	3.77	4.29	3.91	ns
LVC MOS15, Slow, 4 mA	0.64	0.73	0.85	0.85	2.58	2.79	3.10	2.93	2.58	2.79	3.10	2.93	ns
LVC MOS15, Slow, 6 mA	0.64	0.73	0.85	0.85	2.08	2.32	2.68	2.50	2.08	2.32	2.68	2.50	ns
LVC MOS15, Slow, 8 mA	0.64	0.73	0.85	0.85	1.81	1.98	2.23	2.24	1.81	1.98	2.23	2.24	ns
LVC MOS15, Slow, 12 mA	0.64	0.73	0.85	0.85	1.76	1.91	2.13	2.07	1.76	1.91	2.13	2.07	ns
LVC MOS15, Slow, 16 mA	0.64	0.73	0.85	0.85	1.69	1.83	2.04	1.98	1.69	1.83	2.04	1.98	ns
LVC MOS15, Fast, 2 mA	0.64	0.73	0.85	0.85	3.44	3.77	4.28	3.91	3.44	3.77	4.28	3.91	ns
LVC MOS15, Fast, 4 mA	0.64	0.73	0.85	0.85	2.37	2.53	2.78	2.66	2.37	2.53	2.78	2.66	ns
LVC MOS15, Fast, 6 mA	0.64	0.73	0.85	0.85	1.80	2.05	2.42	2.16	1.80	2.05	2.42	2.16	ns
LVC MOS15, Fast, 8 mA	0.64	0.73	0.85	0.85	1.76	1.90	2.11	2.04	1.76	1.90	2.11	2.04	ns
LVC MOS15, Fast, 12 mA	0.64	0.73	0.85	0.85	1.64	1.77	1.97	1.90	1.64	1.77	1.97	1.90	ns
LVC MOS15, Fast, 16 mA	0.64	0.73	0.85	0.85	1.62	1.76	1.96	1.92	1.62	1.76	1.96	1.92	ns
LVC MOS12, Slow, 2 mA	0.72	0.81	0.93	0.95	3.14	3.39	3.75	3.54	3.14	3.39	3.75	3.54	ns
LVC MOS12, Slow, 4 mA	0.72	0.81	0.93	0.95	2.43	2.63	2.93	2.79	2.43	2.63	2.93	2.79	ns
LVC MOS12, Slow, 6 mA	0.72	0.81	0.93	0.95	1.92	2.11	2.41	2.26	1.92	2.11	2.41	2.26	ns
LVC MOS12, Slow, 8 mA	0.72	0.81	0.93	0.95	1.87	2.02	2.25	2.17	1.87	2.02	2.25	2.17	ns
LVC MOS12, Fast, 2 mA	0.72	0.81	0.93	0.95	2.71	2.98	3.39	3.11	2.71	2.98	3.39	3.11	ns
LVC MOS12, Fast, 4 mA	0.72	0.81	0.93	0.95	1.93	2.16	2.51	2.31	1.93	2.16	2.51	2.31	ns
LVC MOS12, Fast, 6 mA	0.72	0.81	0.93	0.95	1.75	1.89	2.11	2.05	1.75	1.89	2.11	2.05	ns
LVC MOS12, Fast, 8 mA	0.72	0.81	0.93	0.95	1.69	1.82	2.02	1.98	1.69	1.82	2.02	1.98	ns
LVDCI_25	0.51	0.57	0.66	0.70	2.05	2.14	2.26	2.26	2.05	2.14	2.26	2.26	ns
LVDCI_18	0.55	0.61	0.71	0.73	2.07	2.23	2.47	2.38	2.07	2.23	2.47	2.38	ns
LVDCI_15	0.64	0.73	0.85	0.85	1.85	2.01	2.24	2.18	1.85	2.01	2.24	2.18	ns

Table 44: IOB Switching Characteristics for the Commercial (XC) Virtex-6 Devices (Cont'd)

I/O Standard	T _{IOPI}				T _{IOOP}				T _{IOTP}				Units
	Speed Grade				Speed Grade				Speed Grade				
	-3	-2	-1	-1L	-3	-2	-1	-1L	-3	-2	-1	-1L	
DIFF_SSTL18_I	0.85	0.94	1.09	1.08	1.47	1.58	1.75	1.73	1.47	1.58	1.75	1.73	ns
DIFF_SSTL18_I_DCI	0.85	0.94	1.09	1.08	1.40	1.51	1.67	1.65	1.40	1.51	1.67	1.65	ns
DIFF_SSTL18_II	0.85	0.94	1.09	1.08	1.39	1.50	1.67	1.66	1.39	1.50	1.67	1.66	ns
DIFF_SSTL18_II_DCI	0.85	0.94	1.09	1.08	1.36	1.47	1.63	1.62	1.36	1.47	1.63	1.62	ns
DIFF_SSTL18_II_T_DCI	0.85	0.94	1.09	1.08	1.40	1.51	1.67	1.65	1.40	1.51	1.67	1.65	ns
DIFF_SSTL15	0.81	0.91	1.06	1.06	1.42	1.54	1.71	1.69	1.42	1.54	1.71	1.69	ns
DIFF_SSTL15_DCI	0.81	0.91	1.06	1.06	1.41	1.52	1.68	1.66	1.41	1.52	1.68	1.66	ns
DIFF_SSTL15_T_DCI	0.81	0.91	1.06	1.06	1.41	1.52	1.68	1.66	1.41	1.52	1.68	1.66	ns

Table 45: IOB Switching Characteristics for the Defense-grade (XQ) Virtex-6 Devices

I/O Standard	T _{IOPI}			T _{IOOP}			T _{IOTP}			Units
	Speed Grade			Speed Grade			Speed Grade			
	-2	-1	-1L	-2	-1	-1L	-2	-1	-1L	
LVDS_25	0.94	1.09	1.08	1.54	2.16	1.62	1.54	2.16	1.62	ns
LVDSEXT_25	0.94	1.09	1.08	1.65	2.20	1.73	1.65	2.20	1.73	ns
HT_25	0.94	1.09	1.08	1.62	2.20	1.69	1.62	2.20	1.69	ns
BLVDS_25	0.94	1.09	1.08	1.50	3.18	1.65	1.50	3.18	1.65	ns
RSDS_25 (point to point)	0.94	1.09	1.08	1.54	2.22	1.62	1.54	2.22	1.62	ns
HSTL_I	0.91	1.06	1.06	1.56	2.44	1.71	1.56	2.44	1.71	ns
HSTL_II	0.91	1.06	1.06	1.56	2.21	1.72	1.56	2.21	1.72	ns
HSTL_III	0.91	1.06	1.06	1.54	2.50	1.69	1.54	2.50	1.69	ns
HSTL_I_18	0.91	1.06	1.06	1.58	2.43	1.72	1.58	2.43	1.72	ns
HSTL_II_18	0.91	1.06	1.06	1.62	2.30	1.78	1.62	2.30	1.78	ns
HSTL_III_18	0.91	1.06	1.06	1.54	2.49	1.69	1.54	2.49	1.69	ns
SSTL2_I	0.91	1.06	1.06	1.60	2.50	1.74	1.60	2.50	1.74	ns
SSTL2_II	0.91	1.06	1.06	1.54	2.49	1.71	1.54	2.49	1.71	ns
SSTL15	0.91	1.06	1.06	1.54	2.07	1.69	1.54	2.07	1.69	ns
LVC MOS25, Slow, 2 mA	0.57	0.66	0.70	5.46	6.01	5.63	5.46	6.01	5.63	ns
LVC MOS25, Slow, 4 mA	0.57	0.66	0.70	3.49	3.79	3.65	3.49	3.79	3.65	ns
LVC MOS25, Slow, 6 mA	0.57	0.66	0.70	2.81	3.08	2.95	2.81	3.08	2.95	ns
LVC MOS25, Slow, 8 mA	0.57	0.66	0.70	2.41	2.72	2.59	2.41	2.72	2.59	ns
LVC MOS25, Slow, 12 mA	0.57	0.66	0.70	1.95	2.23	2.10	1.95	2.23	2.10	ns
LVC MOS25, Slow, 16 mA	0.57	0.66	0.70	2.05	2.29	2.21	2.05	2.29	2.21	ns
LVC MOS25, Slow, 24 mA	0.57	0.66	0.70	1.82	2.24	1.98	1.82	2.24	1.98	ns
LVC MOS25, Fast, 2 mA	0.57	0.66	0.70	5.49	6.04	5.62	5.49	6.04	5.62	ns
LVC MOS25, Fast, 4 mA	0.57	0.66	0.70	3.50	3.82	3.65	3.50	3.82	3.65	ns
LVC MOS25, Fast, 6 mA	0.57	0.66	0.70	2.73	2.99	2.88	2.73	2.99	2.88	ns
LVC MOS25, Fast, 8 mA	0.57	0.66	0.70	2.33	2.65	2.53	2.33	2.65	2.53	ns
LVC MOS25, Fast, 12 mA	0.57	0.66	0.70	1.88	2.08	2.03	1.88	2.08	2.03	ns

I/O Standard Adjustment Measurement Methodology

Input Delay Measurements

Table 47 shows the test setup parameters used for measuring input delay.

Table 47: Input Delay Measurement Methodology

Description	I/O Standard Attribute	$V_L^{(1)(2)}$	$V_H^{(1)(2)}$	$V_{MEAS}^{(1)(4)(5)}$	$V_{REF}^{(1)(3)(5)}$
LVC MOS, 2.5V	LVC MOS25	0	2.5	1.25	—
LVC MOS, 1.8V	LVC MOS18	0	1.8	0.9	—
LVC MOS, 1.5V	LVC MOS15	0	1.5	0.75	—
HSTL (High-Speed Transceiver Logic), Class I & II	HSTL_I, HSTL_II	$V_{REF} - 0.5$	$V_{REF} + 0.5$	V_{REF}	0.75
HSTL, Class III	HSTL_III	$V_{REF} - 0.5$	$V_{REF} + 0.5$	V_{REF}	0.90
HSTL, Class I & II, 1.8V	HSTL_I_18, HSTL_II_18	$V_{REF} - 0.5$	$V_{REF} + 0.5$	V_{REF}	0.90
HSTL, Class III 1.8V	HSTL_III_18	$V_{REF} - 0.5$	$V_{REF} + 0.5$	V_{REF}	1.08
SSTL (Stub Terminated Transceiver Logic), Class I & II, 3.3V	SSTL3_I, SSTL3_II	$V_{REF} - 1.00$	$V_{REF} + 1.00$	V_{REF}	1.5
SSTL, Class I & II, 2.5V	SSTL2_I, SSTL2_II	$V_{REF} - 0.75$	$V_{REF} + 0.75$	V_{REF}	1.25
SSTL, Class I & II, 1.8V	SSTL18_I, SSTL18_II	$V_{REF} - 0.5$	$V_{REF} + 0.5$	V_{REF}	0.90
LVDS (Low-Voltage Differential Signaling), 2.5V	LVDS_25	$1.2 - 0.125$	$1.2 + 0.125$	$0^{(6)}$	—
LVDS EXT (LVDS Extended Mode), 2.5V	LVDS EXT_25	$1.2 - 0.125$	$1.2 + 0.125$	$0^{(6)}$	—
HT (HyperTransport), 2.5V	LDT_25	$0.6 - 0.125$	$0.6 + 0.125$	$0^{(6)}$	—

Notes:

1. The input delay measurement methodology parameters for LVDCI are the same for LVC MOS standards of the same voltage. Input delay measurement methodology parameters for HSLVDCI are the same as for HSTL_II standards of the same voltage. Parameters for all other DCI standards are the same for the corresponding non-DCI standards.
2. Input waveform switches between V_L and V_H .
3. Measurements are made at typical, minimum, and maximum V_{REF} values. Reported delays reflect worst case of these measurements. V_{REF} values listed are typical.
4. Input voltage level from which measurement starts.
5. This is an input voltage reference that bears no relation to the V_{REF} / V_{MEAS} parameters found in IBIS models and/or noted in Figure 6.
6. The value given is the differential input voltage.

Input/Output Delay Switching Characteristics

Table 53: Input/Output Delay Switching Characteristics

Symbol	Description	Speed Grade				Units
		-3	-2	-1	-1L	
IDELAYCTRL						
T _{DLYCCO_RDY}	Reset to Ready for IDELAYCTRL	3.00	3.00	3.00	3.25	μs
F _{IDELAYCTRL_REF}	REFCLK frequency = 200.0 ⁽¹⁾	200	200	200	200	MHz
	REFCLK frequency = 300.0 ⁽¹⁾	300	300	–	–	MHz
IDELAYCTRL_REF_PRECISION	REFCLK precision	±10	±10	±10	±10	MHz
T _{IDELAYCTRL_RPW}	Minimum Reset pulse width	50.00	50.00	50.00	52.50	ns
IODELAY						
T _{IDELAYRESOLUTION}	IODELAY Chain Delay Resolution	1/(32 x 2 x F _{REF})				ps
T _{IDELAYPAT_JIT}	Pattern dependent period jitter in delay chain for clock pattern. ⁽²⁾	0	0	0	0	ps per tap
	Pattern dependent period jitter in delay chain for random data pattern (PRBS 23). ⁽³⁾	±5	±5	±5	±5	ps per tap
	Pattern dependent period jitter in delay chain for random data pattern (PRBS 23). ⁽⁴⁾	±9	±9	±9	±9	ps per tap
T _{IODELAY_CLK_MAX}	Maximum frequency of CLK input to IODELAY	500.00	420.00	300.00	300.00	MHz
T _{IODCCK_CE} / T _{IODCKC_CE}	CE pin Setup/Hold with respect to CK	0.45/ –0.09	0.53/ –0.09	0.65/ –0.09	0.84/ –0.14	ns
T _{IODCK_INC} / T _{IODCKC_INC}	INC pin Setup/Hold with respect to CK	0.23/ –0.02	0.27/ –0.01	0.31/ 0.00	0.27/ –0.04	ns
T _{IODCCK_RST} / T _{IODCKC_RST}	RST pin Setup/Hold with respect to CK	0.57/ –0.08	0.62/ –0.08	0.69/ –0.08	0.74/ –0.13	ns
T _{IODDO_T}	TSCONTROL delay to MUXE/MUXF switching and through IODELAY	Note 5	Note 5	Note 5	Note 5	ps
T _{IODDO_IDATAIN}	Propagation delay through IODELAY	Note 5	Note 5	Note 5	Note 5	ps
T _{IODDO_ODATAIN}	Propagation delay through IODELAY	Note 5	Note 5	Note 5	Note 5	ps

Notes:

1. Average Tap Delay at 200 MHz = 78 ps, at 300 MHz = 52 ps.
2. When HIGH_PERFORMANCE mode is set to TRUE or FALSE.
3. When HIGH_PERFORMANCE mode is set to TRUE
4. When HIGH_PERFORMANCE mode is set to FALSE.
5. Delay depends on IDELAY tap setting. See TRACE report for actual values.

CLB Switching Characteristics

Table 54: CLB Switching Characteristics

Symbol	Description	Speed Grade				Units
		-3	-2	-1	-1L	
Combinatorial Delays						
T _{ILO}	An – Dn LUT address to A	0.06	0.07	0.07	0.09	ns, Max
	An – Dn LUT address to AMUX/CMUX	0.18	0.20	0.22	0.25	ns, Max
	An – Dn LUT address to BMUX_A	0.28	0.31	0.36	0.40	ns, Max

CLB Distributed RAM Switching Characteristics (SLICEM Only)

Table 55: CLB Distributed RAM Switching Characteristics

Symbol	Description	Speed Grade				Units
		-3	-2	-1	-1L	
Sequential Delays						
T _{SHCKO}	Clock to A – B outputs	0.92	1.10	1.36	1.49	ns, Max
T _{SHCKO_1}	Clock to AMUX – BMUX outputs	1.19	1.40	1.71	1.87	ns, Max
Setup and Hold Times Before/After Clock CLK						
T _{DS} /T _{DH}	A – D inputs to CLK	0.62/0.18	0.72/0.20	0.88/0.22	0.98/0.23	ns, Min
T _{AS} /T _{AH}	Address An inputs to clock	0.19/0.52	0.22/0.59	0.27/0.66	0.30/0.75	ns, Min
T _{WS} /T _{WH}	WE input to clock	0.27/0.00	0.32/0.00	0.40/0.00	0.47/–0.03	ns, Min
T _{CECK} /T _{CKCE}	CE input to CLK	0.28/–0.01	0.34/–0.01	0.41/–0.01	0.48/–0.05	ns, Min
Clock CLK						
T _{MPW}	Minimum pulse width	0.70	0.82	1.00	1.04	ns, Min
T _{MCP}	Minimum clock period	1.40	1.64	2.00	2.08	ns, Min

Notes:

1. A Zero “0” Hold Time listing indicates no hold time or a negative hold time. Negative values cannot be guaranteed “best-case”, but if a “0” is listed, there is no positive hold time.
2. T_{SHCKO} also represents the CLK to XMUX output. Refer to TRACE report for the CLK to XMUX path.

CLB Shift Register Switching Characteristics (SLICEM Only)

Table 56: CLB Shift Register Switching Characteristics

Symbol	Description	Speed Grade				Units
		-3	-2	-1	-1L	
Sequential Delays						
T _{REG}	Clock to A – D outputs	1.11	1.30	1.58	1.74	ns, Max
T _{REG_MUX}	Clock to AMUX – DMUX output	1.37	1.60	1.93	2.12	ns, Max
T _{REG_M31}	Clock to DMUX output via M31 output	1.08	1.27	1.55	1.74	ns, Max
Setup and Hold Times Before/After Clock CLK						
T _{WS} /T _{WH}	WE input	0.05/0.00	0.07/0.00	0.09/0.00	0.11/0.03	ns, Min
T _{CECK} /T _{CKCE}	CE input to CLK	0.06/–0.01	0.08/–0.01	0.10/–0.01	0.12/0.02	ns, Min
T _{DS} /T _{DH}	A – D inputs to CLK	0.64/0.18	0.76/0.21	0.94/0.24	1.07/0.23	ns, Min
Clock CLK						
T _{MPW}	Minimum pulse width	0.60	0.70	0.85	0.89	ns, Min

Notes:

1. A Zero “0” Hold Time listing indicates no hold time or a negative hold time. Negative values cannot be guaranteed “best-case”, but if a “0” is listed, there is no positive hold time.

Block RAM and FIFO Switching Characteristics

Table 57: Block RAM and FIFO Switching Characteristics

Symbol	Description	Speed Grade				Units
		-3	-2	-1	-1L	
Block RAM and FIFO Clock-to-Out Delays						
T _{RCKO_DO} and T _{RCKO_DO_REG} ⁽¹⁾	Clock CLK to DOUT output (without output register) ⁽²⁾⁽³⁾	1.60	1.79	2.08	2.36	ns, Max
	Clock CLK to DOUT output (with output register) ⁽⁴⁾⁽⁵⁾	0.60	0.66	0.75	0.83	ns, Max
T _{RCKO_DO_ECC} and T _{RCKO_DO_ECC_REG}	Clock CLK to DOUT output with ECC (without output register) ⁽²⁾⁽³⁾	2.62	2.89	3.30	3.73	ns, Max
	Clock CLK to DOUT output with ECC (with output register) ⁽⁴⁾⁽⁵⁾	0.71	0.77	0.86	0.94	ns, Max
T _{RCKO_CASC} and T _{RCKO_CASC_REG}	Clock CLK to DOUT output with Cascade (without output register) ⁽²⁾	2.49	2.77	3.18	3.61	ns, Max
	Clock CLK to DOUT output with Cascade (with output register) ⁽⁴⁾	1.29	1.41	1.58	1.79	ns, Max
T _{RCKO_FLAGS}	Clock CLK to FIFO flags outputs ⁽⁶⁾	0.74	0.81	0.91	0.98	ns, Max
T _{RCKO_POINTERS}	Clock CLK to FIFO pointers outputs ⁽⁷⁾	0.90	0.98	1.09	1.21	ns, Max
T _{RCKO_SDBIT_ECC} and T _{RCKO_SDBIT_ECC_REG}	Clock CLK to BITERR (with output register)	0.62	0.68	0.76	0.82	ns, Max
	Clock CLK to BITERR (without output register)	2.21	2.46	2.84	3.23	ns, Max
T _{RCKO_PARITY_ECC}	Clock CLK to ECCPARITY in ECC encode only mode	0.86	0.94	1.06	1.18	ns, Max
T _{RCKO_RDADDR_ECC} and T _{RCKO_RDADDR_ECC_REG}	Clock CLK to RDADDR output with ECC (without output register)	0.73	0.79	0.90	1.00	ns, Max
	Clock CLK to RDADDR output with ECC (with output register)	0.76	0.82	0.92	1.02	ns, Max
Setup and Hold Times Before/After Clock CLK						
T _{RCKC_ADDR} /T _{RCKC_ADDR}	ADDR inputs ⁽⁸⁾	0.47/ 0.27	0.53/ 0.29	0.62/ 0.32	0.66/ 0.34	ns, Min
T _{RDCK_DI} /T _{RCKD_DI}	DIN inputs ⁽⁹⁾	0.84/ 0.30	0.95/ 0.32	1.11/ 0.34	1.26/ 0.36	ns, Min
T _{RDCK_DI_ECC} /T _{RCKD_DI_ECC}	DIN inputs with block RAM ECC in standard mode ⁽⁹⁾	0.47/ 0.30	0.52/ 0.32	0.59/ 0.34	0.68/ 0.36	ns, Min
	DIN inputs with block RAM ECC encode only ⁽⁹⁾	0.68/ 0.30	0.75/ 0.32	0.85/ 0.34	0.97/ 0.36	ns, Min
	DIN inputs with FIFO ECC in standard mode ⁽⁹⁾	0.77/ 0.30	0.87/ 0.32	1.02/ 0.34	1.16/ 0.36	ns, Min
T _{RCKC_CLK} /T _{RCKC_CLK}	Inject single/double bit error in ECC mode	0.90/ 0.27	1.02/ 0.28	1.20/ 0.29	1.56/ 0.29	ns, Min
T _{RCKC_RDEN} /T _{RCKC_RDEN}	Block RAM Enable (EN) input	0.31/ 0.26	0.35/ 0.27	0.41/ 0.30	0.44/ 0.31	ns, Min
T _{RCKC_REGCE} /T _{RCKC_REGCE}	CE input of output register	0.18/ 0.25	0.19/ 0.27	0.22/ 0.31	0.24/ 0.33	ns, Min
T _{RCKC_RSTREG} /T _{RCKC_RSTREG}	Synchronous RSTREG input	0.22/ 0.23	0.24/ 0.24	0.28/ 0.26	0.31/ 0.27	ns, Min
T _{RCKC_RSTRAM} /T _{RCKC_RSTRAM}	Synchronous RSTRAM input	0.32/ 0.23	0.36/ 0.24	0.41/ 0.27	0.46/ 0.29	ns, Min

DSP48E1 Switching Characteristics

Table 58: DSP48E1 Switching Characteristics

Symbol	Description	Speed Grade					Units
		-3	-2	-1 (XC)	-1 (XQ)	-1L	
Setup and Hold Times of Data/Control Pins to the Input Register Clock							
$T_{\text{DSPDCK}_{\{A, \text{ACIN}; B, \text{BCIN}\}}_{\{\text{AREG}; \text{BREG}\}}/T_{\text{DSPCKD}_{\{A, \text{ACIN}; B, \text{BCIN}\}}_{\{\text{AREG}; \text{BREG}\}}}$	{A, ACIN, B, BCIN} input to {A, B} register CLK	0.25/ 0.27	0.29/ 0.30	0.35/ 0.34	0.36/ 0.34	0.46/ 0.39	ns
$T_{\text{DSPDCK}_{\text{C_CREG}}/T_{\text{DSPCKD}_{\text{C_CREG}}}}$	C input to C register CLK	0.16/ 0.20	0.19/ 0.22	0.22/ 0.24	0.25/ 0.24	0.33/ 0.30	ns
$T_{\text{DSPDCK}_{\text{D_DREG}}/T_{\text{DSPCKD}_{\text{D_DREG}}}}$	D input to D register CLK	0.07/ 0.31	0.10/ 0.34	0.15/ 0.39	0.16/ 0.39	0.24/ 0.45	ns
Setup and Hold Times of Data Pins to the Pipeline Register Clock							
$T_{\text{DSPDCK}_{\{A, \text{ACIN}, B, \text{BCIN}\}}_{\text{MREG_MULT}}/T_{\text{DSPCKD}_{\{A, \text{ACIN}, B, \text{BCIN}\}}_{\text{MREG_MULT}}}$	{A, ACIN, B, BCIN} input to M register CLK	2.36/ 0.04	2.70/ 0.04	3.21/ 0.04	3.21/ 0.04	3.66/ 0.02	ns
$T_{\text{DSPDCK}_{\{A, D\}}_{\text{ADREG}}/T_{\text{DSPCKD}_{\{A, D\}}_{\text{ADREG}}}$	{A, D} input to AD register CLK	1.24/ 0.10	1.42/ 0.12	1.69/ 0.13	1.69/ 0.13	1.91/ 0.16	ns
Setup and Hold Times of Data/Control Pins to the Output Register Clock							
$T_{\text{DSPDCK}_{\{A, \text{ACIN}, B, \text{BCIN}\}}_{\text{PREG_MULT}}/T_{\text{DSPCKD}_{\{A, \text{ACIN}, B, \text{BCIN}\}}_{\text{PREG_MULT}}}$	{A, ACIN, B, BCIN} input to P register CLK using multiplier	3.83/ −0.13	4.37/ −0.13	5.20/ −0.13	5.20/ −0.13	5.94/ −0.24	ns
$T_{\text{DSPDCK}_{\text{D_PREG_MULT}}/T_{\text{DSPCKD}_{\text{D_PREG_MULT}}}}$	D input to P register CLK	3.62/ −0.47	4.13/ −0.47	4.90/ −0.47	4.90/ −0.47	5.61/ −0.77	ns
$T_{\text{DSPDCK}_{\{A, \text{ACIN}, B, \text{BCIN}\}}_{\text{PREG}}/T_{\text{DSPCKD}_{\{A, \text{ACIN}, B, \text{BCIN}\}}_{\text{PREG}}}$	{A, ACIN, B, BCIN} input to P register CLK not using multiplier	1.59/ −0.13	1.81/ −0.13	2.15/ −0.13	2.15/ −0.13	2.44/ −0.24	ns
$T_{\text{DSPDCK}_{\text{C_PREG}}/T_{\text{DSPCKD}_{\text{C_PREG}}}}$	C input to P register CLK	1.42/ −0.10	1.61/ −0.10	1.91/ −0.10	1.91/ −0.10	2.16/ −0.19	ns
$T_{\text{DSPDCK}_{\{\text{PCIN}, \text{CARRYCASCIN}, \text{MULTSIGNIN}\}}_{\text{PREG}}/T_{\text{DSPCKD}_{\{\text{PCIN}, \text{CARRYCASCIN}, \text{MULTSIGNIN}\}}_{\text{PREG}}}$	{PCIN, CARRYCASCIN, MULTSIGNIN} input to P register CLK	1.23/ −0.02	1.41/ −0.02	1.67/ −0.02	1.67/ −0.02	1.91/ −0.07	ns
Setup and Hold Times of the CE Pins							
$T_{\text{DSPDCK}_{\{\text{CEA}; \text{CEB}\}}_{\{\text{AREG}; \text{BREG}\}}/T_{\text{DSPCKD}_{\{\text{CEA}; \text{CEB}\}}_{\{\text{AREG}; \text{BREG}\}}}$	{CEA; CEB} input to {A; B} register CLK	0.14/ 0.19	0.17/ 0.22	0.22/ 0.25	0.22/ 0.25	0.30/ 0.28	ns
$T_{\text{DSPDCK}_{\text{CEC_CREG}}/T_{\text{DSPCKD}_{\text{CEC_CREG}}}}$	CEC input to C register CLK	0.15/ 0.18	0.18/ 0.20	0.24/ 0.23	0.24/ 0.23	0.31/ 0.26	ns
$T_{\text{DSPDCK}_{\text{CED_DREG}}/T_{\text{DSPCKD}_{\text{CED_DREG}}}}$	CED input to D register CLK	0.20/ 0.12	0.24/ 0.13	0.31/ 0.14	0.31/ 0.14	0.43/ 0.16	ns
$T_{\text{DSPDCK}_{\text{CEM_MREG}}/T_{\text{DSPCKD}_{\text{CEM_MREG}}}}$	CEM input to M register CLK	0.16/ 0.19	0.20/ 0.21	0.26/ 0.25	0.26/ 0.25	0.32/ 0.28	ns
$T_{\text{DSPDCK}_{\text{CEP_PREG}}/T_{\text{DSPCKD}_{\text{CEP_PREG}}}}$	CEP input to P register CLK	0.32/ 0.02	0.38/ 0.02	0.46/ 0.03	0.46/ 0.03	0.54/ 0.04	ns
Setup and Hold Times of the RST Pins							
$T_{\text{DSPDCK}_{\{\text{RSTA}; \text{RSTB}\}}_{\{\text{AREG}; \text{BREG}\}}/T_{\text{DSPCKD}_{\{\text{RSTA}; \text{RSTB}\}}_{\{\text{AREG}; \text{BREG}\}}}$	{RSTA, RSTB} input to {A, B} register CLK	0.27/ 0.17	0.31/ 0.19	0.38/ 0.22	0.38/ 0.22	0.41/ 0.25	ns
$T_{\text{DSPDCK}_{\text{RSTC_CREG}}/T_{\text{DSPCKD}_{\text{RSTC_CREG}}}}$	RSTC input to C register CLK	0.18/ 0.08	0.20/ 0.08	0.23/ 0.09	0.23/ 0.09	0.27/ 0.11	ns
$T_{\text{DSPDCK}_{\text{RSTD_DREG}}/T_{\text{DSPCKD}_{\text{RSTD_DREG}}}}$	RSTD input to D register CLK	0.28/ 0.15	0.32/ 0.16	0.38/ 0.19	0.38/ 0.19	0.45/ 0.21	ns
$T_{\text{DSPDCK}_{\text{RSTM_MREG}}/T_{\text{DSPCKD}_{\text{RSTM_MREG}}}}$	RSTM input to M register CLK	0.20/ 0.24	0.23/ 0.26	0.26/ 0.30	0.26/ 0.30	0.29/ 0.34	ns

Table 58: DSP48E1 Switching Characteristics (Cont'd)

Symbol	Description	Speed Grade					Units
		-3	-2	-1 (XC)	-1 (XQ)	-1L	
$T_{DSPDO_PCIN, CARRYCASCIN, MULTSIGNIN_PCOUT, CARRYCASCOUT, MULTSIGNOUT}$	{PCIN, CARRYCASCIN, MULTSIGNIN} input to {PCOUT, CARRYCASCOUT, MULTSIGNOUT} output	1.28	1.46	1.72	1.72	2.06	ns
Clock to Outs from Output Register Clock to Output Pins							
$T_{DSPCKO_P, CARRYOUT_PREG}$	CLK (PREG) to {P, CARRYOUT} output	0.38	0.43	0.50	0.50	0.57	ns
$T_{DSPCKO_PCOUT, CARRYCASCOUT, MULTSIGNOUT_PREG}$	CLK (PREG) to {CARRYCASCOUT, PCOUT, MULTSIGNOUT} output	0.50	0.56	0.66	0.66	0.76	ns
Clock to Outs from Pipeline Register Clock to Output Pins							
$T_{DSPCKO_P, CARRYOUT_MREG}$	CLK (MREG) to {P, CARRYOUT} output	1.72	1.96	2.30	2.30	2.69	ns
$T_{DSPCKO_PCOUT, CARRYCASCOUT, MULTSIGNOUT_MREG}$	CLK (MREG) to {PCOUT, CARRYCASCOUT, MULTSIGNOUT} output	1.81	2.06	2.43	2.43	2.88	ns
$T_{DSPCKO_P, CARRYOUT_ADREG_MULT}$	CLK (ADREG) to {P, CARRYOUT} output	2.79	3.16	3.72	3.72	4.32	ns
$T_{DSPCKO_PCOUT, CARRYCASCOUT, MULTSIGNOUT_ADREG_MULT}$	CLK (ADREG) to {PCOUT, CARRYCASCOUT, MULTSIGNOUT} output	2.87	3.26	3.84	3.84	4.51	ns
Clock to Outs from Input Register Clock to Output Pins							
$T_{DSPCKO_P, CARRYOUT_AREG, BREG_MULT}$	CLK (AREG, BREG) to {P, CARRYOUT} output using multiplier	3.97	4.52	5.36	5.36	6.20	ns
$T_{DSPCKO_P, CARRYOUT_AREG, BREG}$	CLK (AREG, BREG) to {P, CARRYOUT} output not using multiplier	1.70	1.93	2.27	2.27	2.65	ns
$T_{DSPCKO_P, CARRYOUT_CREG}$	CLK (CREG) to {P, CARRYOUT} output	1.70	1.93	2.27	2.27	2.80	ns
$T_{DSPCKO_P, CARRYOUT_DREG_MULT}$	CLK (DREG) to {P, CARRYOUT} output	3.89	4.44	5.25	5.25	6.07	ns
Clock to Outs from Input Register Clock to Cascading Output Pins							
$T_{DSPCKO_ACOUT, BCOUT_AREG, BREG}$	CLK (AREG, BREG) to {P, CARRYOUT} output	0.66	0.76	0.89	0.89	1.01	ns
$T_{DSPCKO_PCOUT, CARRYCASCOUT, MULTSIGNOUT_AREG, BREG_MULT}$	CLK (AREG, BREG) to {PCOUT, CARRYCASCOUT, MULTSIGNOUT} output using multiplier	4.05	4.63	5.49	5.49	6.39	ns
$T_{DSPCKO_PCOUT, CARRYCASCOUT, MULTSIGNOUT_AREG, BREG}$	CLK (AREG, BREG) to {PCOUT, CARRYCASCOUT, MULTSIGNOUT} output not using multiplier	1.79	2.03	2.40	2.40	2.84	ns
$T_{DSPCKO_PCOUT, CARRYCASCOUT, MULTSIGNOUT_DREG_MULT}$	CLK (DREG) to {PCOUT, CARRYCASCOUT, MULTSIGNOUT} output using multiplier	3.98	4.54	5.38	5.38	6.26	ns
$T_{DSPCKO_PCOUT, CARRYCASCOUT, MULTSIGNOUT_CREG}$	CLK (CREG) to {PCOUT, CARRYCASCOUT, MULTSIGNOUT} output	1.78	2.03	2.40	2.40	2.99	ns

Table 59: Configuration Switching Characteristics (Cont'd)

Symbol	Description	Speed Grade				Units
		-3	-2	-1	-1L	
T _{SMCKBY}	CCLK to BUSY out in readback at 2.5V	6	6	6	7	ns, Max
	CCLK to BUSY out in readback at 1.8V	6	6	6	7	ns, Max
F _{SMCK}	Maximum Frequency with respect to nominal CCLK	100	100	100	70	MHz, Max
F _{RBCK}	Maximum Readback Frequency with respect to nominal CCLK	100	100	100	60	MHz, Max
F _{MCCKTOL}	Frequency tolerance, master mode with respect to nominal CCLK	55	55	55	60	%
Boundary-Scan Port Timing Specifications						
T _{TAPTCK} /T _{TCKTAP}	TMS and TDI Setup time before TCK/ Hold time after TCK	3.0/2.0	3.0/2.0	3.0/2.0	4.0/2.0	ns, Min
T _{TCKTDO}	TCK falling edge to TDO output valid at 2.5V	6	6	6	7	ns, Max
	TCK falling edge to TDO output valid at 1.8V	6	6	6	7	ns, Max
F _{TCK}	Maximum configuration TCK clock frequency	66	66	66	33	MHz, Max
F _{TCKB_MIN}	Minimum boundary-scan TCK clock frequency when using IEEE Std 1149.6 (AC-JTAG). Minimum operating temperature for IEEE Std 1149.6 is 0°C.	15	15	15	15	MHz, Min
F _{TCKB}	Maximum boundary-scan TCK clock frequency	66	66	66	33	MHz, Max
BPI Master Flash Mode Programming Switching						
T _{BPICCO} ⁽²⁾	ADDR[25:0], RS[1:0], FCS_B, FOE_B, FWE_B outputs valid after CCLK rising edge at 2.5V	6	6	6	7	ns
	ADDR[25:0], RS[1:0], FCS_B, FOE_B, FWE_B outputs valid after CCLK rising edge at 1.8V	6	6	6	7	ns
T _{BPIDCC} /T _{BPICCD}	Setup/Hold on D[15:0] data input pins	4.0/0.0	4.0/0.0	4.0/0.0	5.0/0.0	ns
T _{INITADDR}	Minimum period of initial ADDR[25:0] address cycles	3	3	3	3	CCLK cycles
SPI Master Flash Mode Programming Switching						
T _{SPIDCC} /T _{SPIDCCD}	DIN Setup/Hold before/after the rising CCLK edge	3.0/0.0	3.0/0.0	3.0/0.0	3.5/0.0	ns
T _{SPICCM}	MOSI clock to out at 2.5V	6	6	6	7	ns
	MOSI clock to out at 1.8V	6	6	6	7	ns
T _{SPICFC}	FCS_B clock to out at 2.5V	6	6	6	7	ns
	FCS_B clock to out at 1.8V	6	6	6	7	ns
T _{FSINIT} /T _{FSINITH}	FS[2:0] to INIT_B rising edge Setup and Hold	2	2	2	2	µs
CCLK Output (Master Modes)						
T _{MCCKL}	Master CCLK clock Low time duty cycle	45/55	45/55	45/55	40/60	%, Min/Max
T _{MCCKH}	Master CCLK clock High time duty cycle	45/55	45/55	45/55	40/60	%, Min/Max
CCLK Input (Slave Modes)						
T _{SCCKL}	Slave CCLK clock minimum Low time	2.5	2.5	2.5	2.5	ns, Min
T _{SCCKH}	Slave CCLK clock minimum High time	2.5	2.5	2.5	2.5	ns, Min
Dynamic Reconfiguration Port (DRP) for MMCM Before and After DCLK						
F _{DCK}	Maximum frequency for DCLK	200	200	200	200	MHz
T _{MMCMCKD_DADDR} / T _{MMCMCKD_DADDR}	DADDR Setup/Hold	1.25/ 0.00	1.40/ 0.00	1.63/ 0.00	1.64/ 0.00	ns

Table 59: Configuration Switching Characteristics (Cont'd)

Symbol	Description	Speed Grade				Units
		-3	-2	-1	-1L	
$T_{\text{MMCMDCK_DI}}/$ $T_{\text{MMCCKD_DI}}$	DI Setup/Hold	1.25/ 0.00	1.40/ 0.00	1.63/ 0.00	1.64/ 0.00	ns
$T_{\text{MMCMDCK_DEN}}/$ $T_{\text{MMCCKD_DEN}}$	DEN Setup/Hold time	1.25/ 0.00	1.40/ 0.00	1.63/ 0.00	1.64/ 0.00	ns
$T_{\text{MMCMDCK_DWE}}/$ $T_{\text{MMCCKD_DWE}}$	DWE Setup/Hold time	1.25/ 0.00	1.40/ 0.00	1.63/ 0.00	1.64/ 0.00	ns
$T_{\text{MMCCKO_DO}}$	CLK to out of DO ⁽³⁾	2.60	3.02	3.64	3.68	ns
$T_{\text{MMCCKO_DRDY}}$	CLK to out of DRDY	0.32	0.34	0.38	0.38	ns

Notes:

1. To support longer delays in configuration, use the design solutions described in [UG360: Virtex-6 FPGA Configuration User Guide](#).
2. Only during configuration, the last edge is determined by a weak pull-up/pull-down resistor in the I/O.
3. DO will hold until next DRP operation.

Clock Buffers and Networks

Table 60: Global Clock Switching Characteristics (Including BUFGCTRL)

Symbol	Description	Devices	Speed Grade				Units
			-3	-2	-1	-1L	
$T_{\text{BCCCK_CE}}/T_{\text{BCCCK_CE}}^{(1)}$	CE pins Setup/Hold	All	0.11/ 0.00	0.13/ 0.00	0.16/ 0.00	0.13/ 0.00	ns
$T_{\text{BCCCK_S}}/T_{\text{BCCCK_S}}^{(1)}$	S pins Setup/Hold	All	0.11/ 0.00	0.13/ 0.00	0.16/ 0.00	0.13/ 0.00	ns
$T_{\text{BCKO_O}}^{(2)}$	BUFGCTRL delay from I0/I1 to O	All	0.07	0.08	0.10	0.10	ns
Maximum Frequency							
F_{MAX}	Global clock tree (BUFG)	All except LX760	800	750	700	667	MHz
		LX760	N/A	700	700	667	MHz

Notes:

1. $T_{\text{BCCCK_CE}}$ and $T_{\text{BCCCK_S}}$ must be satisfied to assure glitch-free operation of the global clock when switching between clocks. These parameters do not apply to the BUFGMUX_VIRTEX4 primitive that assures glitch-free operation. The other global clock setup and hold times are optional; only needing to be satisfied if device operation requires simulation matches on a cycle-for-cycle basis when switching between clocks.
2. $T_{\text{BCKO_O}}$ (BUFG delay from I0 to O) values are the same as $T_{\text{BCKO_O}}$ values.

Table 61: Input/Output Clock Switching Characteristics (BUFIO)

Symbol	Description	Speed Grade				Units
		-3	-2	-1	-1L	
$T_{\text{BIOCKO_O}}$	Clock to out delay from I to O	0.14	0.16	0.18	0.21	ns
Maximum Frequency						
F_{MAX}	I/O clock tree (BUFIO)	800	800	710	710	MHz

Table 62: Regional Clock Switching Characteristics (BUFR)

Symbol	Description	Speed Grade				Units
		-3	-2	-1	-1L	
$T_{\text{BRCKO_O}}$	Clock to out delay from I to O	0.56	0.62	0.73	0.82	ns
$T_{\text{BRCKO_O_BYP}}$	Clock to out delay from I to O with Divide Bypass attribute set	0.28	0.31	0.36	0.41	ns

Table 69: Global Clock Input Setup and Hold With MMCM

Symbol	Description	Device	Speed Grade				Units
			-3	-2	-1	-1L	
Input Setup and Hold Time Relative to Global Clock Input Signal for LVCMOS25 Standard.(1)							
T _{PSMMCMGC} / T _{PHMMCMGC}	No Delay Global Clock Input and IFF(2) with MMCM	XC6VLX75T	1.45/ −0.18	1.57/ −0.18	1.72/ −0.18	1.78/ −0.08	ns
		XC6VLX130T	1.53/ −0.18	1.65/ −0.18	1.81/ −0.18	1.87/ −0.07	ns
		XC6VLX195T	1.54/ −0.17	1.66/ −0.17	1.82/ −0.17	1.87/ −0.08	ns
		XC6VLX240T	1.54/ −0.17	1.66/ −0.17	1.82/ −0.17	1.87/ −0.08	ns
		XC6VLX365T	1.55/ −0.18	1.67/ −0.18	1.83/ −0.18	1.87/ −0.07	ns
		XC6VLX550T	N/A	1.84/ −0.17	2.02/ −0.17	2.06/ −0.06	ns
		XC6VLX760	N/A	2.26/ −0.13	2.49/ −0.13	2.06/ −0.03	ns
		XC6VSX315T	1.56/ −0.18	1.68/ −0.18	1.84/ −0.18	1.89/ −0.08	ns
		XC6VSX475T	N/A	1.85/ −0.23	2.03/ −0.23	2.07/ −0.13	ns
		XC6VHX250T	1.52/ −0.17	1.64/ −0.17	1.80/ −0.17	N/A	ns
		XC6VHX255T	1.52/ −0.12	1.64/ −0.12	1.85/ −0.12	N/A	ns
		XC6VHX380T	1.68/ −0.16	1.81/ −0.16	1.99/ −0.16	N/A	ns
		XC6VHX565T	N/A	1.81/ −0.01	1.99/ −0.01	N/A	ns
		XQ6VLX130T	N/A	1.65/ −0.18	1.81/ −0.18	1.87/ −0.07	ns
		XQ6VLX240T	N/A	1.66/ −0.17	1.82/ −0.17	1.87/ −0.08	ns
		XQ6VLX550T	N/A	N/A	2.02/ −0.17	2.06/ −0.06	ns
		XQ6VSX315T	N/A	1.68/ −0.18	1.84/ −0.18	1.89/ −0.08	ns
		XQ6VSX475T	N/A	N/A	2.03/ −0.23	2.07/ −0.13	ns

Notes:

- Setup and Hold times are measured over worst case conditions (process, voltage, temperature). Setup time is measured relative to the Global Clock input signal using the slowest process, highest temperature, and lowest voltage. Hold time is measured relative to the Global Clock input signal using the fastest process, lowest temperature, and highest voltage.
- IFF = Input Flip-Flop or Latch
- Use IBIS to determine any duty-cycle distortion incurred using various standards.

Table 70: Clock-Capable Clock Input Setup and Hold With MMCM

Symbol	Description	Device	Speed Grade				Units
			-3	-2	-1	-1L	
Input Setup and Hold Time Relative to Clock-capable Clock Input Signal for LVCMOS25 Standard. ⁽¹⁾							
T _{PSMMCMCC} / T _{PHMMCMCC}	No Delay Clock-capable Clock Input and IFF ⁽²⁾ with MMCM	XC6VLX75T	1.56/ −0.25	1.69/ −0.25	1.86/ −0.25	1.91/ −0.15	ns
		XC6VLX130T	1.64/ −0.25	1.78/ −0.25	1.95/ −0.25	2.00/ −0.14	ns
		XC6VLX195T	1.65/ −0.24	1.79/ −0.24	1.96/ −0.24	2.01/ −0.15	ns
		XC6VLX240T	1.65/ −0.24	1.79/ −0.24	1.96/ −0.24	2.01/ −0.15	ns
		XC6VLX365T	1.66/ −0.25	1.79/ −0.25	1.97/ −0.25	2.02/ −0.15	ns
		XC6VLX550T	N/A	1.97/ −0.24	2.16/ −0.24	2.19/ −0.14	ns
		XC6VLX760	N/A	2.39/ −0.20	2.63/ −0.20	2.21/ −0.10	ns
		XC6VSX315T	1.67/ −0.25	1.80/ −0.25	1.98/ −0.25	2.03/ −0.16	ns
		XC6VSX475T	N/A	1.98/ −0.29	2.17/ −0.29	2.21/ −0.20	ns
		XC6VHX250T	1.63/ −0.24	1.76/ −0.24	1.94/ −0.24	N/A	ns
		XC6VHX255T	1.63/ −0.19	1.76/ −0.19	1.99/ −0.19	N/A	ns
		XC6VHX380T	1.80/ −0.23	1.94/ −0.23	2.13/ −0.23	N/A	ns
		XC6VHX565T	N/A	1.94/ −0.08	2.13/ −0.08	N/A	ns
		XQ6VLX130T	N/A	1.78/ −0.25	1.95/ −0.25	2.00/ −0.14	ns
		XQ6VLX240T	N/A	1.79/ −0.24	1.96/ −0.24	2.01/ −0.15	ns
		XQ6VLX550T	N/A	N/A	2.16/ −0.24	2.19/ −0.14	ns
		XQ6VSX315T	N/A	1.80/ −0.25	1.98/ −0.25	2.03/ −0.16	ns
		XQ6VSX475T	N/A	N/A	2.17/ −0.29	2.21/ −0.20	ns

Notes:

- Setup and Hold times are measured over worst case conditions (process, voltage, temperature). Setup time is measured relative to the Global Clock input signal using the slowest process, highest temperature, and lowest voltage. Hold time is measured relative to the Global Clock input signal using the fastest process, lowest temperature, and highest voltage.
- IFF = Input Flip-Flop or Latch
- Use IBIS to determine any duty-cycle distortion incurred using various standards.

Table 72: Package Skew

Symbol	Description	Device	Package	Value	Units
T _{PKGSKEW}	Package Skew ⁽¹⁾	XC6VLX75T	FF484	95	ps
			FF784	146	ps
		XC6VLX130T	FF484	95	ps
			FF784	146	ps
			FF1156	165	ps
		XC6VLX195T	FF784	145	ps
			FF1156	182	ps
		XC6VLX240T	FF784	146	ps
			FF1156	182	ps
			FF1759	187	ps
		XC6VLX365T	FF1156	189	ps
			FF1759	184	ps
		XC6VLX550T	FF1759	196	ps
			FF1760	249	ps
		XC6VLX760	FF1760	236	ps
		XC6VSX315T	FF1156	168	ps
			FF1759	190	ps
		XC6VSX475T	FF1156	168	ps
			FF1759	204	ps
		XC6VHX250T	FF1154	166	ps
		XC6VHX255T	FF1155	168	ps
			FF1923	228	ps
		XC6VHX380T	FF1154	159	ps
			FF1155	172	ps
			FF1923	227	ps
			FF1924	220	ps
		XC6VHX565T	FF1923	232	ps
			FF1924	197	ps
		XQ6VLX130T	RF784	146	ps
			RF1156	165	ps
			FFG1156	165	ps
		XQ6VLX240T	RF784	146	ps
			RF1156	182	ps
			FFG1156	182	ps
			RF1759	187	ps
		XQ6VLX550T	RF1759	196	ps
		XQ6VSX315T	RF1156	168	ps
			FFG1156	168	ps
			RF1759	190	ps
		XQ6VSX475T	RF1156	168	ps
			FFG1156	168	ps
			RF1759	204	ps

Notes:

- These values represent the worst-case skew between any two SelectIO resources in the package: shortest flight time to longest flight time from Pad to Ball (7.0 ps per mm).
- Package trace length information is available for these device/package combinations. This information can be used to deskew the package.

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